

mK - SPM mK - Scanning Probe Microscope

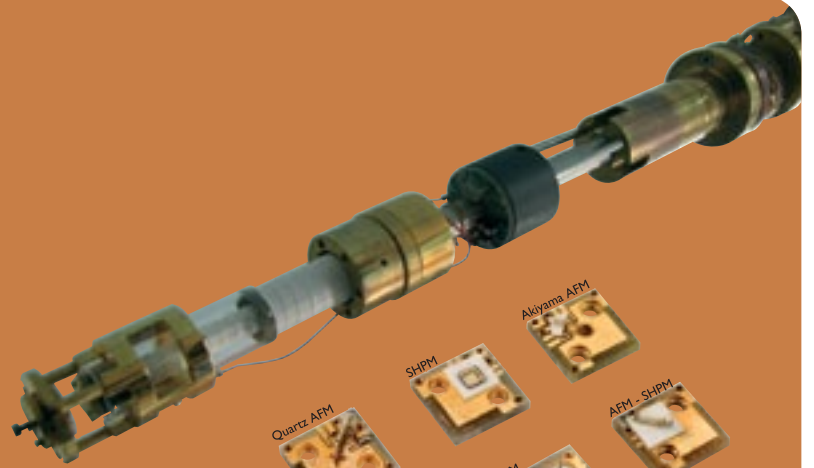


NANOMAGNETICS
INSTRUMENTS

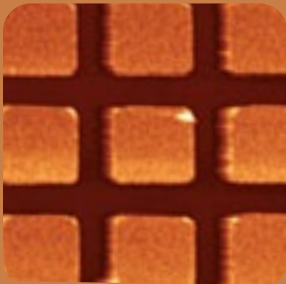


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STM Image of 6 μ m pitch
Calibration Grating, 300 mK



3D STM Image of 6 μ m pitch
Calibration Grating, 300 mK



Images courtesy of
Dr. M. Deshmukh
Tata Institute for Research, INDIA

System Specifications

Imaging Modes	: STM, AFM, contact AFM, non-contact AFM, MFM, Quartz/Akiyama AFM, EFM, SNOM (in development)		
Scan Size	: Large Area Scan Head 150 x 150 μ m @ 300 K 36 x 36 μ m @ 77 K 18 x 18 μ m @ 4.2 K	Standart Scan Head 52 x 52 μ m @ 300K 14 x 14 μ m @ 77 K 6 x 6 μ m @ 4.2 K	Small Area Scan Head 8 x 8 μ m @ 300 K 3.5 x 3.5 μ m @ 77 K 1.5 x 1.5 μ m @ 4.2 K
Z Range	: 7.0 μ m @ 300 K 1.8 μ m @ 77 K 0.8 μ m @ 4.2 K	4.8 μ m @ 300 K 1.2 μ m @ 77 K 0.5 μ m @ 4.2 K	2.4 μ m @ 300 K 0.6 μ m @ 77K 0.25 μ m @ 4.2K
Head Dimensions	: 23.6 mm OD x 125 mm or 25.4 mm OD x 100 mm		
Sample Approach	: Stick-slip type; 10 mm Z, ϕ 3 mm XY range with 50 - 800 nm step size		
Sample Size	: 15 x 15 x 5 mm maximum		
Temperature Range	: 10 mK - 300 K (Limited by the cryogenic system)		
Magnetic Field	: >16 T		
Compatibility	: Oxford Instruments' Dilution Refrigerators and He ³ systems. Can be customised to fit in to other mK systems if free space permits.		

Suitable cryostats are also available

Software upgrades are free for lifetime

Note: Specifications are subject to change without notice.

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